

2SA1858

Silicon PNP epitaxial planar type

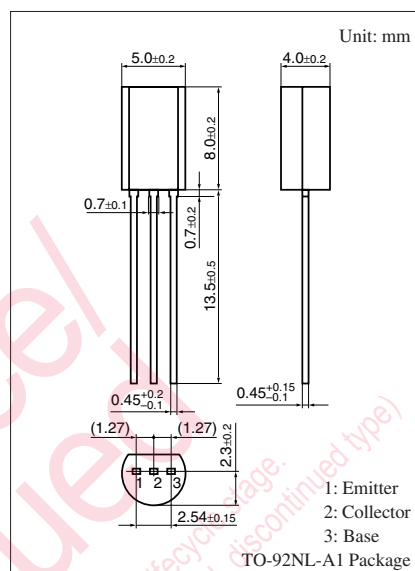
For low-frequency power amplification

■ Features

- High collector-emitter voltage (Base open) V_{CEO}

■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	V_{CBO}	-300	V
Collector-emitter voltage (Base open)	V_{CEO}	-300	V
Emitter-base voltage (Collector open)	V_{EBO}	-5	V
Collector current	I_C	-70	mA
Peak collector current	I_{CP}	-100	mA
Collector power dissipation	P_C	1	W
Junction temperature	T_j	150	$^\circ\text{C}$
Storage temperature	T_{stg}	-55 to +150	$^\circ\text{C}$



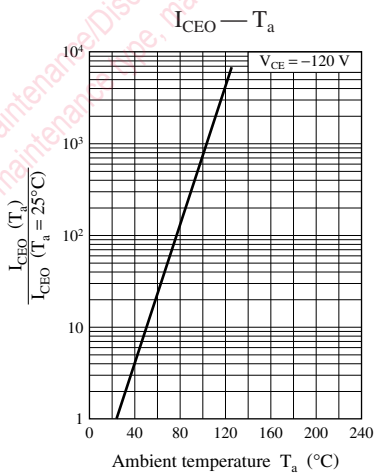
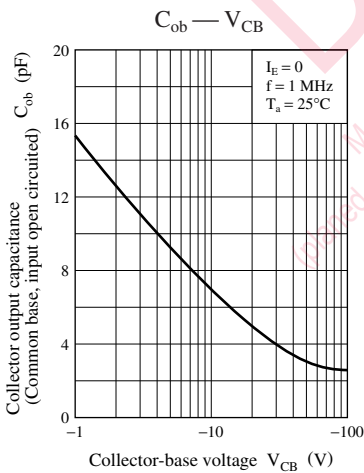
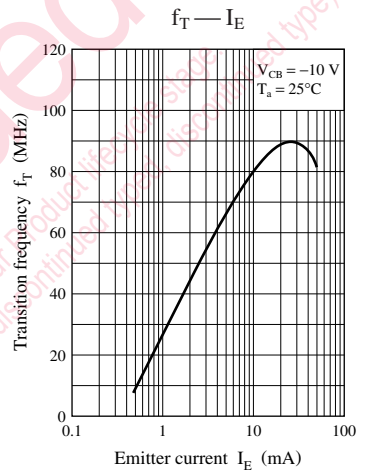
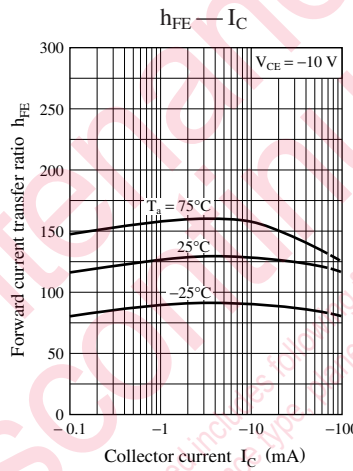
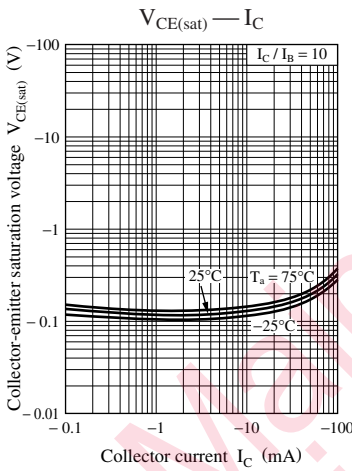
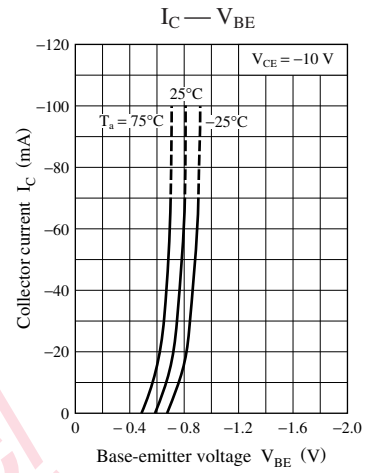
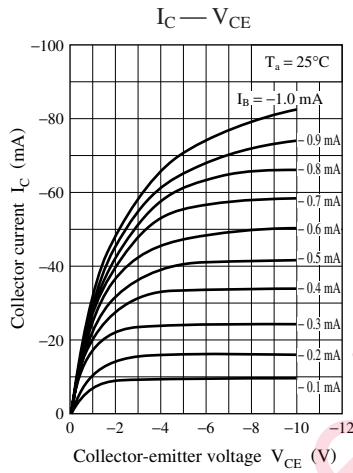
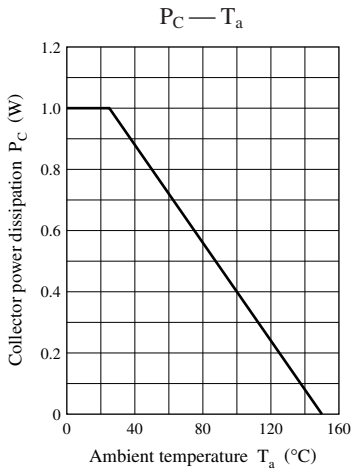
■ Electrical Characteristics $T_a = 25^\circ\text{C} \pm 3^\circ\text{C}$

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Collector-emitter voltage (Base open)	V_{CEO}	$I_C = -100 \mu\text{A}$, $I_B = 0$	-300			V
Emitter-base voltage (Collector open)	V_{EBO}	$I_E = -1 \mu\text{A}$, $I_C = 0$	-5			V
Forward current transfer ratio *	h_{FE}	$V_{CE} = -10 \text{ V}$, $I_C = -5 \text{ mA}$	30		150	—
Collector-emitter saturation voltage	$V_{CE(sat)}$	$I_C = -10 \text{ mA}$, $I_B = -1 \text{ mA}$			-0.6	V
Transition frequency	f_T	$V_{CB} = -10 \text{ V}$, $I_E = 10 \text{ mA}$, $f = 200 \text{ MHz}$	50			MHz
Collector output capacitance (Common base, input open circuited)	C_{ob}	$V_{CB} = -10 \text{ V}$, $I_E = 0$, $f = 1 \text{ MHz}$		7		pF

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. *: Rank classification

Rank	P	Q
h_{FE}	30 to 100	60 to 150



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